

East Searched
6/22/04 - Mt.

L Number	Hits	Search Text	DB	Time stamp
1	13	Drussel near Zane.inv.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/22 14:07
2	387	"Singulation methods"and opening and separating near axis	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/22 14:23
3	5	"Singulation methods"and opening and separating near axis and cutting near tool	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/22 14:23
-	2	6664480.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/22 14:07
-	25	("3780431" "4316320" "4426773" "4532839" "4621552" "4742615" "4791721" "4926546" "5311407" "5448451" "5483857" "5488886" "5521430" "5652185" "5773764" "5831218" "5854741" "5886398" "5894648" "5960961" "6047470" "6114189" "6239380" "6246015" "6342727").PN.	USPAT	2004/06/22 10:14
-	3	"Singulation methods" and 29/\$.ccls. and 174/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/22 10:16
-	99	"Singulation methods"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/22 10:21
-	8476	"Singulation methods"and (74/250; 174/260 ; 174/261 ; 361/760 ; 361/79E ; 361/719; 361/777 ; 361/846 ; 29/841 ; 428/901).ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/22 14:21
-	2	"Singulation methods" and (74/250; 174/260 ; 174/261 ; 361/760 ; 361/79E ; 361/719; 361/777 ; 361/846 ; 29/841 ; 428/901).ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/22 10:22

-	4	"Singulation methods" and (174/250; 174/260 ; 174/261 ; 361/760 ; 361/79E ; 361/719; 361/777 ; 361/846 ; 29/841 ; 428/901).ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/22 10:23
-	3	"Singulation methods" and (174/250; 174/260 ; 174/261 ; 361/760 ; 361/79E ; 361/719; 361/777 ; 361/846 ; 29/841 ; 428/901).ccls. and 29/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/22 10:23

	Title	Current OR
1	Use of a reference fiducial on a semiconductor package to monitor and control a singulation method	438/401
2	Singulation methods and substrates for use with same	29/846
3	Method for determining the location of a droplet on a component	438/14
4	Use of a reference fiducial on a semiconductor package to monitor and control a singulation method	438/460
5	Singulation methods and substrates for use with same	174/250
6	Method for establishing reference coordinates for a point on a component	438/16
7	Use of a reference fiducial on a semiconductor package to monitor and control a singulation method	257/708
8	Singulation methods and substrates for use with same	174/255
9	Method for determining the concentration of contamination on a component	438/14
10	Method for establishing reference coordinates for a point on a component	438/14
11	Singulation methods and substrates for use with same	174/250
12	Singulation methods	29/847

	Title	Current OR
13	Apparatus for establishing reference coordinates for a point on a component	118/712

	Current XRef
1	438/462
2	174/250; 174/255; 29/831
3	
4	438/401
5	174/268; 257/E23.004
6	
7	257/797
8	257/E23.004; 29/846; 361/771
9	
10	
11	257/E23.004; 29/841; 29/846; 361/719; 361/766; 361/792; 428/901
12	29/412; 29/415; 29/846; 83/35